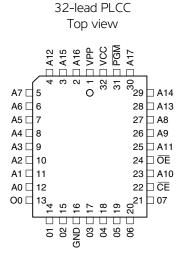
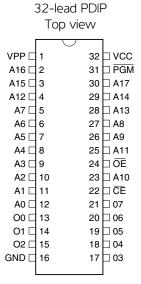


2. Pin configurations

Pin name	Function
A0 - A17	Addresses
00 - 07	Outputs
CE	Chip enable
ŌĒ	Output enable
PGM	Program strobe

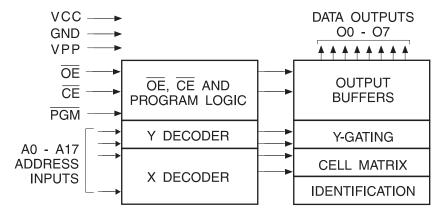




3. System considerations

Switching between active and standby conditions via the chip enable pin may produce transient voltage excursions. Unless accommodated by the system design, these transients may exceed datasheet limits, resulting in device nonconformance. At a minimum, a $0.1\mu\text{F}$, high-frequency, low inherent inductance, ceramic capacitor should be utilized for each device. This capacitor should be connected between the V_{CC} and ground terminals of the device, as close to the device as possible. Additionally, to stabilize the supply voltage level on printed circuit boards with large EPROM arrays, a $4.7\mu\text{F}$ bulk electrolytic capacitor should be utilized, again connected between the V_{CC} and ground terminals. This capacitor should be positioned as close as possible to the point where the power supply is connected to the array.

Figure 3-1. Block diagram



2

4. Absolute maximum ratings*

Temperature under bias55°C to +125°C
Storage temperature65°C to +150°C
Voltage on any pin with respect to ground2.0V to +7.0V ⁽¹⁾
Voltage on A9 with respect to ground2.0V to +14.0V ⁽¹⁾
V _{PP} supply voltage with respect to ground2.0V to +14.0V ⁽¹⁾

*NOTICE: Stresses beyond those listed under "Absolute maximum ratings" may cause permanent damage to the device. This is a stress rating only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may

affect device reliability.

Note: 1. Minimum voltage is -0.6V DC, which may undershoot to -2.0V for pulses of less than 20ns. Maximum output pin voltage is $V_{CC} + 0.75V$ DC, which may overshoot to +7.0V for pulses of less than 20ns.

5. DC and AC characteristics

Table 5-1. Operating modes

Mode/Pin	Œ	ŌĒ	PGM	Ai	V _{PP}	Outputs
Read	V _{IL}	$V_{\rm IL}$	X ⁽¹⁾	Ai	X	D _{OUT}
Output disable	X	V_{IH}	X	X	X	High-Z
Standby	V _{IH}	X	X	X	X	High-Z
Rapid program ⁽²⁾	V _{IL}	V_{IH}	V _{IL}	Ai	V _{PP}	D _{IN}
PGM verify	V _{IL}	V_{IL}	V _{IH}	Ai	V _{PP}	D _{OUT}
PGM inhibit	V _{IH}	X	X	X	V _{PP}	High-Z
Product identification ⁽⁴⁾	V _{IL}	$V_{\rm IL}$	X	$A9 = V_{H}^{(3)}$ $A0 = V_{IH} \text{ or } V_{IL}$ $A1 - A17 = V_{IL}$	X	Identification code

Notes:

- 1. X can be V_{IL} or V_{IH} .
- 2. Refer to programming characteristics.
- 3. $V_H = 12.0 \pm 0.5V$.
- 4. Two identifier bytes may be selected. All Ai inputs are held low (V_{\parallel}) except A9, which is set to $V_{H'}$, and A0, which is toggled low (V_{\parallel}) to select the manufacturer's identification byte and high (V_{\parallel}) to select the device code byte.

Table 5-2. DC and AC operating conditions for read operation

		Atmel AT27C020			
		-55	-90		
	Ind.	-40°C - 85°C	-40°C - 85°C		
Operating temperature (case)	Auto.		-40°C − 125°C		
V _{CC} power supply		5V ± 10%	5V ± 10%		





Table 5-3. DC and operating characteristics for read operation

Symbol	Parameter	Condition	Min	Max	Units
ILI	Input load current	$V_{IN} = 0V \text{ to } V_{CC} \text{ (Com., Ind.)}$		±1.0	μΑ
I _{LO}	Output leakage current	$V_{OUT} = OV \text{ to } V_{CC} \text{ (Com., Ind.)}$		±5.0	μΑ
I _{PP} ⁽²⁾	V _{PP} ⁽¹⁾ read/standby current	$V_{PP} = V_{CC}$		±10	μΑ
)/ (1) -tt	I_{SB1} (CMOS), $\overline{CE} = V_{CC} \pm 0.3V$		100	μΑ
I _{SB}	V _{CC} ⁽¹⁾ standby current	I_{SB2} (TTL), \overline{CE} = 2.0 to V_{CC} + 0.5V		1.0	mA
I _{CC}	V _{CC} active current	$f = 5MHz$, $I_{OUT} = 0mA$, $\overline{CE} = V_{IL}$		25	mA
V _{IL}	Input low voltage		-0.6	0.8	V
V _{IH}	Input high voltage		2.0	V _{CC} + 0.5	V
V _{OL}	Output low voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output high voltage	I _{OH} = -400μA	2.4		V

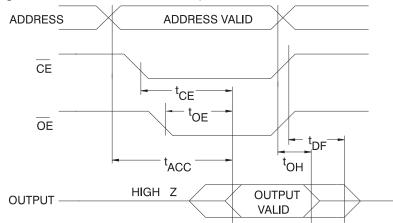
Notes:

- 1. V_{CC} must be applied simultaneously or before V_{PP} , and removed simultaneously or after V_{PP}
- 2. V_{PP} may be connected directly to V_{CC} except during programming. The supply current would then be the sum of I_{CC} and I_{PP} .

Table 5-4. AC characteristics for read operation

			Atmel AT27C020				
			-5	55	-90		
Symbol	Parameter	Condition	Min	Max	Min	Max	Units
t _{ACC} ⁽³⁾	Address to output delay	CE = OE = V _{IL}		55		90	ns
t _{CE} ⁽²⁾	CE to output delay	$\overline{OE} = V_{IL}$		55		90	ns
t _{OE} ⁽²⁾⁽³⁾	OE to output delay	CE = V _{IL}		20		35	ns
t _{DF} ⁽⁴⁾⁽⁵⁾	OE or CE high to outputfloat, Whichever occurred first			18		20	ns
t _{OH}	Output hold from address, $\overline{\text{CE}}$ or $\overline{\text{OE}}$, Whichever occurred first		7		0		ns

Figure 5-1. AC waveforms for read operation⁽¹⁾

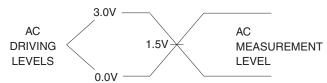


Notes: 1. Timing measurement references are 0.8V and 2.0V. Input AC drive levels are 0.45V and 2.4V, unless otherwise specified.

- 2. $\overline{\text{OE}}$ may be delayed up to t_{CE} t_{OE} after the falling edge of $\overline{\text{CE}}$ without impact on t_{CE} .
- 3. $\overline{\text{OE}}$ may be delayed up to t_{ACC} t_{OE} after the address is valid without impact on t_{ACC} .
- 4. This parameter is only sampled, and is not 100% tested.
- 5. Output float is defined as the point when data is no longer driven.

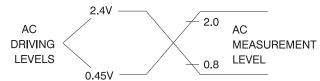
Figure 5-2. Input test waveforms and measurement levels

For -55 devices only:



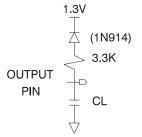
 t_R , t_F < 5ns (10% to 90%)

For -90 devices only:



 t_R , t_F < 20ns (10% to 90%)

Figure 5-3. Output test load



Note: CL = 100pF including jig capacitance, except -55 devices, where CL = 30pF





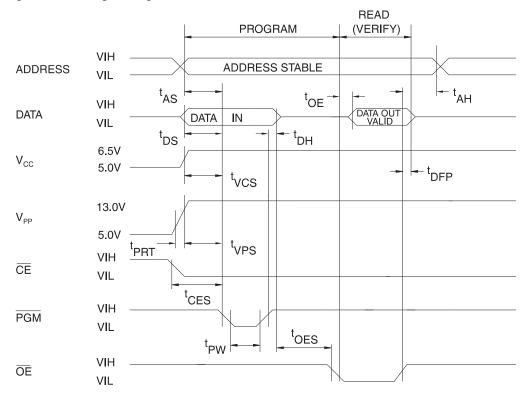
Table 5-5. Pin capacitance

 $f = 1MHz, T = 25^{\circ}C^{(1)}$

Symbol	Тур	Max	Units	Conditions
C _{IN}	4	8	pF	$V_{IN} = OV$
C _{OUT}	8	12	pF	V _{OUT} = 0V

Note: 1. Typical values for nominal supply voltage. This parameter is only sampled, and is not 100% tested.

Figure 5-4. Programming waveforms (1)



Note:

- 1. The input timing reference is 0.8V for $\rm V_{IL}$ and 2.0V for $\rm V_{IH}$
- 2. t_{OE} and t_{DFP} are characteristics of the device, but must be accommodated by the programmer
- 3. When programming the Atmel AT27C020, a $0.1\mu F$ capacitor is required across V_{pp} and ground to suppress voltage transients

Table 5-6. DC programming characteristics

 $T_A = 25 \pm 5$ °C, $V_{CC} = 6.5 \pm 0.25$ V, $V_{PP} = 13.0 \pm 0.25$ V

			Limits		
Symbol	Parameter	Test conditions	Min	Max	Units
I _{LI}	Input load current	$V_{IN} = V_{IL}, V_{IH}$		±10	μΑ
V _{IL}	Input low level		-0.6	0.8	V
V _{IH}	Input high level		2.0	V _{CC} + 1.0	V
V _{OL}	Output low voltage	I _{OL} = 2.1mA		0.4	V
V _{OH}	Output high voltage	I _{OH} = -400μA	2.4		V
I _{CC2}	V _{CC} supply current (program and verify)			40	mA
I _{PP2}	V _{pp} supply current	$\overline{CE} = \overline{PGM} = V_{IL}$		20	mA
V _{ID}	A9 product identification voltage		11.5	12.5	V

Table 5-7. AC programming characteristics

 $T_A = 25 \pm 5$ °C, $V_{CC} = 6.5 \pm 0.25$ V, $V_{PP} = 13.0 \pm 0.25$ V

			Limits		
Symbol Parameter		Test condition (1)	Min	Max	Units
t _{AS}	Address setup time		2		μs
t _{CES}	CE setup time		2		μs
t _{OES}	OE setup time	Input rise and fall times:	2		μs
t _{DS}	Data setup time	(10% to 90%) 20ns	2		μs
t _{AH}	Address hold time	Input pulse levels:	0		μs
t _{DH}	Data hold time	0.45V to 2.4V	2		μs
t _{DFP}	OE high to output float delay ⁽²⁾		0	130	ns
t _{VPS}	V _{PP} setup time	Input timing reference level: 0.8V to 2.0V	2		μs
t _{VCS}	V _{CC} setup time	0.07 to 2.07	2		μs
t _{PW}	PGM program pulse width ⁽³⁾	Output timing reference level:	95	105	μs
t _{OE}	Data valid from OE	0.8V to 2.0V		150	ns
t _{PRT}	V _{PP} pulse rise time during programming		50		ns

Notes:

- 1. V_{CC} must be applied simultaneously with or before V_{pp} and removed simultaneously with or after V_{pp} .
- 2. This parameter is only sampled and is not 100% tested. Output float is defined as the point where data is no longer driven. See timing diagram.
- 3. Program pulse width tolerance is $100\mu s \pm 5\%$.





Table 5-8. The Atmel AT27C020 integrated product identification code

	Pins									
Codes	Α0	07	O6	O5	04	О3	O2	01	00	Hex data
Manufacturer	0	0	0	0	1	1	1	1	0	1E
Device type	1	1	0	0	0	0	1	1	0	86

6. Rapid programming algorithm

A 100 μ s \overline{PGM} pulse width is used to program. The address is set to the first location. V_{CC} is raised to 6.5V and V_{PP} is raised to 13.0V. Each address is first programmed with one 100 μ s \overline{PGM} pulse without verification. Then a verification/reprogramming loop is executed for each address. In the event a byte fails to pass verification, up to 10 successive 100 μ s pulses are applied with a verification after each pulse. If the byte fails to verify after 10 pulses have been applied, the part is considered failed. After the byte verifies properly, the next address is selected until all have been checked. V_{PP} is then lowered to 5.0V and V_{CC} to 5.0V. All bytes are read again and compared with the original data to determine if the device passes or fails.

START ADDR = FIRST LOCATION $V_{CC} = 6.5V$ $V_{PP} = 13.0V$ PROGRAM ONE 100 μ S PULSE INCREMENT ADDRESS NO LAST ADDR.? YES ADDR = FIRST LOCATION INCREMENT ADDRESS X = 0NO **PASS** FAIL LAST VERIFY INCREMENT X ADDR.? BYTE YES NO PROGRAM ONE 100 μ S PULSE X = 10? YES $V_{CC} = 5.0V$ $V_{PP} = 5.0V$ COMPARE FAIL DEVICE ALL BYTES TO ORIGINAL FAILED DATA

PASS

DEVICE PASSED

Figure 6-1. Rapid programming algorithm





7. Ordering information

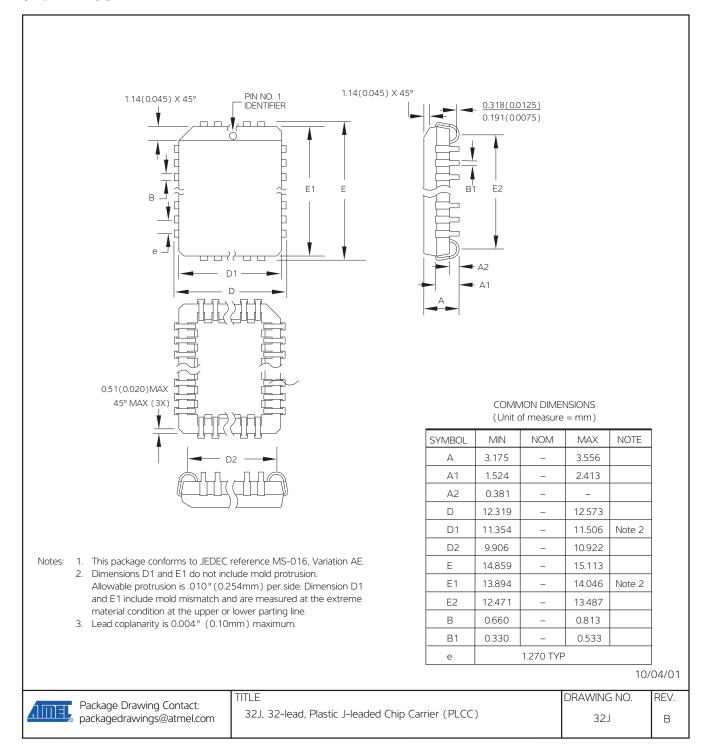
Green package (Pb/halide-free)

t _{ACC}	I _{CC} (mA)					
(ns)	Active	Standby	Atmel ordering code	Package	Lead finish	Operation range
55	25	0.1	AT27C020 -55JU AT27C 020 -55PU	32J 32P6	Matte tin Matte Tin	Industrial (-40°C to 85°C)
90	25	0.1	AT27C 020-90 JU AT27C 020-90 PU	32J 32P6	Matte tin Matte tin	Industrial (-40°C to 85°C)

Package type				
32J	32J 32-lead, plastic, J-leaded chip carrier (PLCC)			
32P6	32-lead, 0.600" wide, plastic, dual inline package (PDIP)			

8. Packaging information

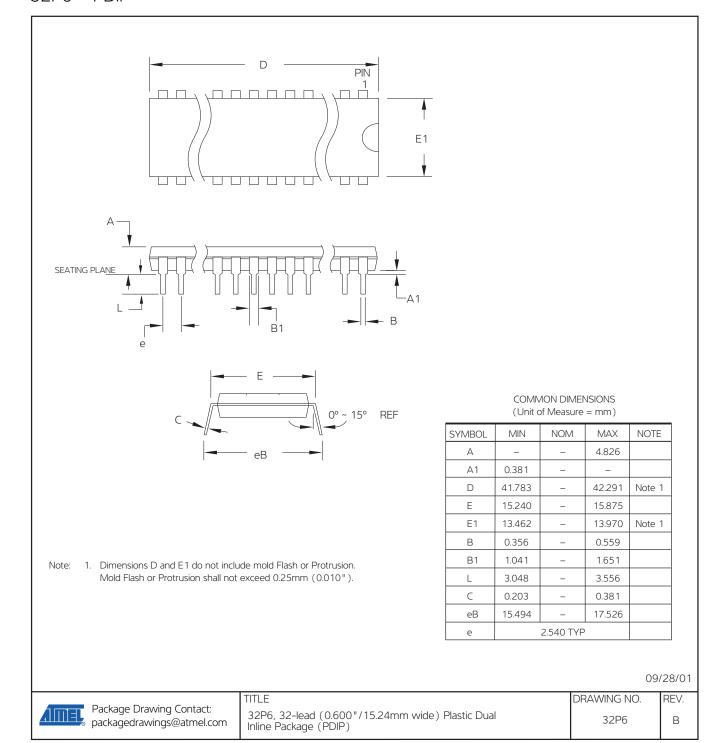
32J – PLCC







32P6 - PDIP



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9. Revision history

Doc. Rev.	Date	Comments
0570H	04/2011	Remove TSOP package Add lead finish to ordering information
0570G	12/2007	





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